



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant(s):

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Art Unit: 2816

Title:

SETUP/HOLD TIME CONTROL DEVICE

Amendment & Reply

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Applicant herein responds to the Office Action mailed May 5, 2004, for the above-captioned application.

Please reconsider the Application as follows.

Amendments

1. (Currently Amended) A <u>device for controlling a setup/hold</u> setup/hole time <u>of an input signal control apparatus</u>, comprising:

a driver for outputting a global bus line control signal by <u>amplifying driving</u> an output signal of an <u>from an</u> input buffer;

a signal delay unit for delaying the global bus line control signal selectively connected to the driver;

a decoding unit for outputting a test mode delay signal by decoding a test control signal for determining to control setup/hold time corresponding to the global bus line control signal, a test mode entry signal, and a test mode exit signal end-signal; and

a delay control unit for controlling the setup/hold setup/hold time of the global bus line control signal by selectively connecting the signal delay unit to the driver according to a state of the test mode delay signal.

- 2. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal control device</u> according to claim 1, further comprising a first latch for latching and outputting the global bus line control signal in <u>synchronous to synchronization with</u> a clock signal.
- 3. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal control device</u> according to claim 1, wherein the driver comprises an inverter chain <u>including an even number of inverters connected in series</u> for non-inverting and delaying <u>and logically non-reversing the output an output signal from the of the input buffer connected in series</u>.
- 4. (Currently Amended) The <u>device for controlling a setup/hold time control device</u> of an input signal according to claim 1, wherein the signal delay unit comprises:
- a first capacitor unit connected selectively to a first node of the driver <u>controlled</u> by the delay control unit; and

a second capacitor unit connected selectively to a second node of the driver <u>controlled</u> by the delay control unit.

- 5. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal control device</u> according to claim 4, wherein the first capacitor unit and the second capacitor unit are MOS capacitors.
- 6. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal control device</u> according to claim 4, wherein the delay control unit comprises:

a first delay control unit for delaying the setup/hold time of the global bus line control signal by selectively connecting the first capacitor unit to the first node according to a state of a first state of the test mode delay signal; and

a second delay control unit for advancing the setup/hold time of the global bus line control signal by selectively connecting the second capacitor unit to the second node according to a state of a second state of the test mode test mode delay signal.

- 7. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal eontrol device</u> according to claim 6, wherein the first delay control unit comprises a first transmission gate and a second transmission gate for receiving the first test mode delay signal through a NMOS gate, and receiving <u>an inversion of</u> the first test mode delay signal inverted through a PMOS gate to selectively connect the first MOS capacitor unit to the first node.
- 8. (Currently Amended) The <u>device for controlling a setup/hold time control device</u> of an input signal according to claim 6, wherein the second delay control unit comprises a third transmission gate and a fourth transmission gate for receiving the second test mode delay signal through a PMOS gate, and receiving <u>an inversion of</u> the second test mode delay signal inverted through a NMOS gate to selectively connect the second capacitor unit to the second node.
- 9. (Currently Amended) The <u>device for controlling a setup/hold time control device</u>
 of an input signal according to claim 6, wherein the decoding unit connects the first capacitor

unit to the first node by outputting setting the first test mode delay signal at a high level when the test control signal is at a high level, and disconnects intercepts connection between the second capacitor unit and the second node by outputting setting the second test mode delay signal at a high level when the test control signal is at a low level.

10. (Currently Amended) The <u>device for controlling a setup/hold time eontrol device</u> of an input signal according to claim 9, wherein the decoding unit comprises:

a logic unit for logically operating the test control signal and the test mode entry signal to output a first output signal and a second output signal;

a second latch for latching the first test mode delay signal according to the first output signal and the test mode exit signal end signal; and

a third latch for latching the second test mode delay signal according to the second output signal and the test mode exit signal end signal.

11. (Currently Amended) The <u>device for controlling a setup/hold time of an input signal control device</u> according to claim 10, wherein the logic unit comprises:

a first NAND gate for NANDing the test control signal and the test mode entry signal to output the first output signal; and

a second NAND gate for NANDing the test mode entry signal and the inverted test mode entry inverted of the test control signal to output the second output signal.

- 12. (Currently Amended) The <u>device for controlling a setup/hold time control device</u> of an input signal according to claim 10, wherein the second latch comprises a <u>third thrid NAND</u> gate and a fourth NAND gate <u>that are cross-coupled to for feeding back each output signal as an input signal</u> each other.
- 13. (Currently Amended) The <u>device for controlling a setup/hold time eontrol device</u> of an input signal according to claim 10, wherein the third latch comprises a fifth NAND gate and a sixth NAND gate that are cross-coupled to for feeding back each output signal as an input signal each other.